


<b>Search Notes</b> 	<b>Application/Control No.</b> 10571866	<b>Applicant(s)/Patent Under Reexamination</b> VEELAERT ET AL.
	<b>Examiner</b> YUN QIAN	<b>Art Unit</b> 4162

SEARCHED			
Class	Subclass	Date	Examiner
	EAST search in PG-pub, PAT, Dewent, EPO and JPO; 536/128 text and 127/65, 67, 71 text.	7/7/2008	yq
	Consult with Curtis Mayes	7/8/2008	yq
536	128	4/23/2009	yq

SEARCH NOTES			
Search Notes		Date	Examiner
Updated search		4/23/09	yq
updated search		11/14/2009	yq
Updated search		4/12/2010	yq

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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